SDAS203C - APRIL 1982 - REVISED JANUARY 1995

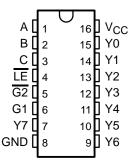
- Combines Decoder and 3-Bit Address Latch
- Incorporates Two Output Enables to Simplify Cascading
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

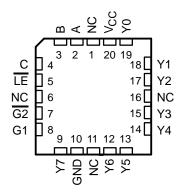
SN54ALS137A. SN74ALS137A. SN74AS137 are 3-line to 8-line decoders/ demultiplexers with latches on the three address inputs. When the latch-enable (LE) input is low, the devices act as decoders/demultiplexers. When LE goes from low to high, the address present at the select (A, B, and C) inputs is stored in the latches. Further address changes are ignored as long as LE remains high. The output-enable controls (G1 and $\overline{G2}$) control the outputs independently of the select or latch-enable inputs. All of the outputs are forced high if G1 is low or G2 is high. These devices are ideally suited for implementing glitch-free decoders in strobed (stored-address) applications in bus-oriented systems.

The SN54ALS137A is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS137A and SN74AS137 are characterized for operation from 0°C to 70°C.

SN54ALS137A . . . J PACKAGE SN74ALS137A, SN74AS137 . . . D OR N PACKAGE (TOP VIEW)



SN54ALS137A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

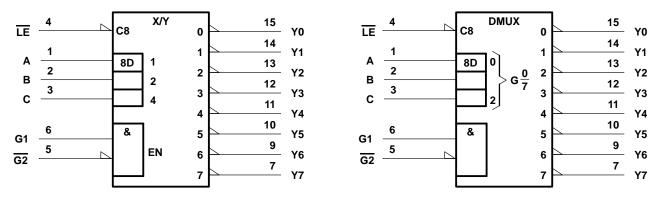
FUNCTION TABLE

INPUTS							OUT	ште					
ENABLE			SELECT				OUTPUTS						
LE	G1	G2	C	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Х	Χ	Н	Х	Х	Х	Н	Н	Н	Н	Н	Н	Н	Н
Х	L	Χ	Χ	Χ	Χ	Н	Н	Н	Н	Н	Н	Н	Н
L	Н	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
L	Н	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н
L	Н	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н
L	Н	L	L	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
L	Н	L	Н	L	L	Н	Н	Н	Н	L	Н	Н	Н
L	Н	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н
L	Н	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н
L	Н	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L
Н	Н	L	Х	Х	Х	Out	puts corr	espondir	ng to stor	ed addre	ess = L; a	all others	s = H



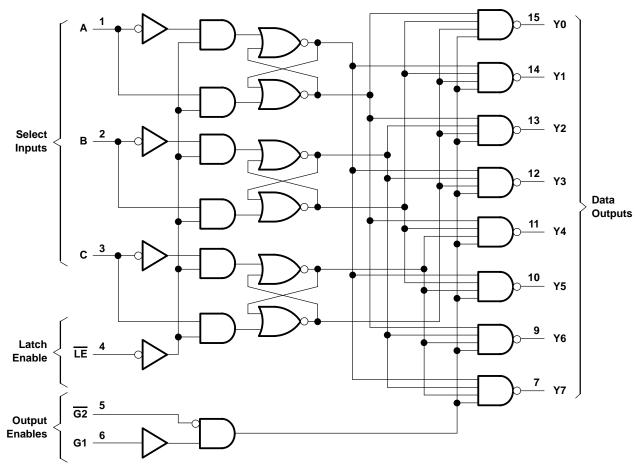
SDAS203C - APRIL 1982 - REVISED JANUARY 1995

logic symbols (alternatives)†



 $[\]dagger$ These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.



SDAS203C - APRIL 1982 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	
Operating free-air temperature range, T _A : SN54ALS137A	-55°C to 125°C
SN74ALS137A	0°C to 70°C
Storage temperature range	-65°C to 150°C

recommended operating conditions

		SNS	4ALS13	7A	SN74ALS137A		UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-0.4			-0.4	mA
lOL	Low-level output current			4			8	mA
t _W	Pulse duration, LE low	15			10			ns
t _{su}	Setup time at A, B, and C before LE↑	15			10			ns
th	Hold time at A, B, and C after LE↑	5			5		·	ns
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN	SN54ALS137A			SN74ALS137A		
PARAMETER	1531 CC	TEST CONDITIONS		TYP [‡]	MAX	MIN	TYP‡	MAX	UNIT
V _{IK}	$V_{CC} = 4.5 \text{ V},$	$I_{ } = -18 \text{ mA}$			-1.5			-1.5	V
Voн	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		V
Val	VCC = 4.5 V	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V
VOL	vCC = 4.5 v	$I_{OL} = 8 \text{ mA}$					0.35	0.5	٧
Ц	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lін	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
I _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
ΙΟ [§]	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
Icc	V _{CC} = 5.5 V			5	11		5	11	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS203C - APRIL 1982 - REVISED JANUARY 1995

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C (C _L : R _L : T _A :	UNIT				
			SN54AL MIN	S137A MAX	SN74AL MIN	S137A MAX		
t _{PLH}	A, B, C		5	25	5	20		
t _{PHL}		Y	6	25	6	20	ns	
t _{PLH}	G 2	Y	4	15	3	12		
t _{PHL}		· · · · · · · · · · · · · · · · · · ·	5	18	4	15	ns	
t _{PLH}	G1	Y	5	21	4	17		
t _{PHL}	GI		5	19	4	15	ns	
t _{PLH}	LE	Y	7	27	6	22	ns	
^t PHL	LE	1	7	25	7	20	115	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted) ‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN74AS137	0°C to 70°C
Storage temperature range	. −65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN74AS137			UNIT
		MIN	NOM	MAX	UNII
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
ІОН	High-level output current			-2	mA
loL	Low-level output current			20	mA
t _W	Pulse duration, LE low	6.5			ns
t _{su}	Setup time at A, B, and C before LE↑	4			ns
th	Hold time at A, B, and C after LE↑	1			ns
TA	Operating free-air temperature	0		70	°C

SDAS203C - APRIL 1982 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			SN74AS137		
PARAMETER	TEST COND	MIN	TYP [†]	MAX	UNIT	
VIK	$V_{CC} = 4.5 V,$	I _I = –18 mA			-1.2	V
VOH	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V
V _{OL}	$V_{CC} = 4.5 V$,	$I_{OL} = 20 \text{ mA}$		0.35	0.5	٧
ΙĮ	$V_{CC} = 5.5 V$,	V _I = 7 V			0.1	mA
liн	$V_{CC} = 5.5 V$,	V _I = 2.7 V			20	μΑ
I _{ΙL}	$V_{CC} = 5.5 V$,	V _I = 0.4 V			-1	mA
lo [‡]	$V_{CC} = 5.5 V$,	V _O = 2.25 V	-30		- 112	mA
Icc	V _{CC} = 5.5 V			15	24	mA

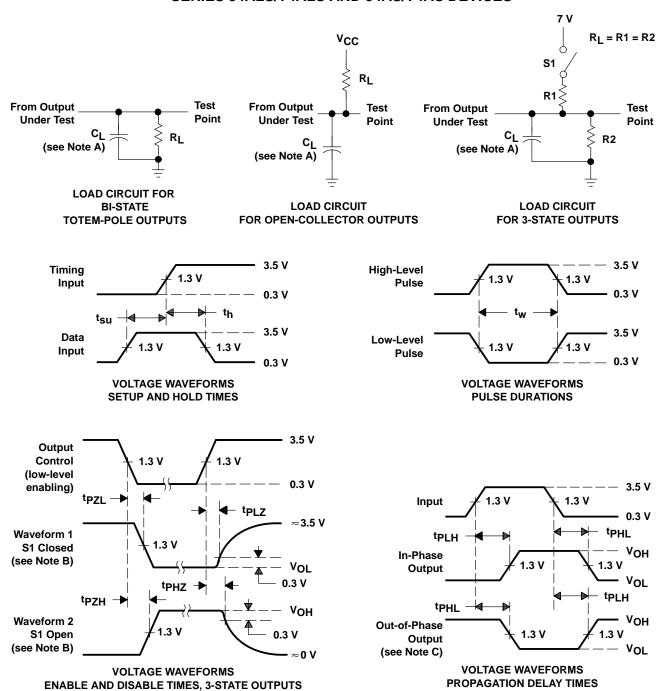
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 C _L = 50 pF R _L = 500 Ω T _A = MIN to	UNIT	
			MIN	MAX	
^t PLH	A, B, C	Y	2	12.5	ns
^t PHL		'	2	12.5	115
t _{PLH}	G 2	Y	2	8	ns
^t PHL		1	2	8.5	115
t _{PLH}	G1	Y	2	10	ns
^t PHL		'	2	9	115
tPLH	Œ	Y	3	13.5	ns
^t PHL	LE	'	3	14	115

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- All input pulses have the following characteristics: PRR \leq 1 MHz, $t_{\Gamma} = t_{f} = 2$ ns, duty cycle = 50%.
- The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated